

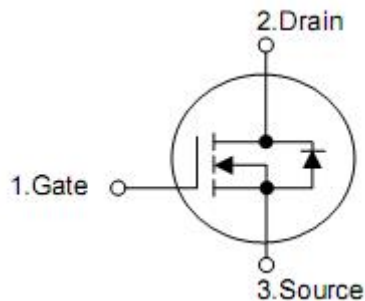
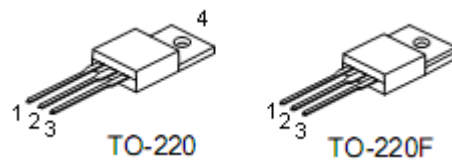
## 1. Description

The KIA12N60H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

## 2. Features

- n  $R_{DS(on)} = 0.53\Omega$  @  $V_{GS} = 10\text{ V}$
- n Low gate charge ( typical 52nC)
- n Fast switching capability
- n avalanche energy specified
- n Improved dv/dt capability

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source
4	Drain

#### 4. Absolute maximum ratings

(TC= 25 °C , unless otherwise specified)

Parameter	Symbol	Rating		Units	
		TO-220	TO-220F		
Drain-source voltage	$V_{DSS}$	600		V	
Drain-source voltage	$V_{GSS}$	± 30		V	
Drain current continuous	$I_D$	$T_C=25\text{ °C}$	12.0	12.0*	A
		$T_C=100\text{ °C}$	7.4	7.4*	A
Drain current pulsed (note 1)	$I_{DP}$	48.0	48*	A	
Avalanche energy	Repetitive (note 1)	23.1		mJ	
	Single pulse (note 2)	865		mJ	
Peak diode recovery dv/dt (note 3)	dv/dt	4.5		V/ns	
Total power dissipation	$P_D$	$T_C=25\text{ °C}$	231	54	W
		derate above 25 °C	1.85	0.43	W/°C
Junction temperature	$T_J$	+150		°C	
Storage temperature	$T_{STG}$	-55~+150		°C	

\*Drain current limited by maximum junction temperature.

#### 5. Thermal characteristics

Parameter	Symbol	Rating		Unit
		TO-220	TO-220F	
Thermal resistance,Junction--ambient	$R_{thJA}$	62.5		°C/W
Thermal resistance,case-to-sink typ.	$R_{thCS}$	0.5	-	°C/W
Thermal resistance,Junction-case	$R_{thJC}$	0.54	2.33	°C/W

## 6. Electrical characteristics

(T<sub>J</sub>=25°C, unless otherwise notes)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Off characteristics						
Drain-source breakdown voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	600	-	-	V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V	-	-	1	μA
		V <sub>DS</sub> =480V, T <sub>C</sub> =125°C	-	-	10	μA
Gate-body leakage current	Forward	I <sub>GSS</sub>	V <sub>GS</sub> =30V, V <sub>DS</sub> =0V	-	-	100
	Reverse					-100
Breakdown voltage temperature coefficient	ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	I <sub>D</sub> =250μA	-	0.7	-	V/°C
On characteristics						
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2.0	-	4.0	V
Static drain-source on-resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =6.0A	-	0.53	0.65	Ω
Dynamic characteristics						
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1MHz	-	1850	-	pF
Output capacitance	C <sub>oss</sub>		-	180	-	pF
Reverse transfer capacitance	C <sub>rss</sub>		-	20	-	pF
Switching characteristics						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =300V, I <sub>D</sub> =12.0A, R <sub>G</sub> =25Ω(note4,5)	-	30	-	ns
Rise time	t <sub>r</sub>		-	90	-	ns
Turn-off delay time	t <sub>d(off)</sub>		-	140	-	ns
fall time	t <sub>f</sub>		-	90	-	ns
Total gate charge	Q <sub>g</sub>	V <sub>DS</sub> =480V, I <sub>D</sub> =12.0A V <sub>GS</sub> =10V, (note4,5)	-	52	-	nC
Gate-source charge	Q <sub>gs</sub>		-	8.5	-	nC
Gate-drain charge	Q <sub>gd</sub>		-	20	-	nC
Drain-source diode characteristics						
Drain-source diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>SD</sub> =12.0A	-	-	1.4	V
Continuous drain-source current	I <sub>SD</sub>		-	-	12.0	A
Pulsed drain-source current	I <sub>SM</sub>		-	-	48.0	A
Reverse recovery time	t <sub>rr</sub>	I <sub>SD</sub> =12.0A dI <sub>SD</sub> /dt=100A/μs (note4)	-	430	-	ns
Reverse recovery charge	Q <sub>rr</sub>		-	5.0	-	μC

Note: 1. repetitive rating : pulse width limited by maximum junction temperature

2. L=11mH, I<sub>AS</sub>=12.0A, V<sub>DD</sub>=50V, R<sub>G</sub>=25Ω, starting T<sub>J</sub>=25°C

3. I<sub>SD</sub>≤12.0A, di/dt≤200A/μs, V<sub>DD</sub>≤BV<sub>DSS</sub>, starting T<sub>J</sub>=25 °C

4. Pulse test: pulse width≤300μs, duty cycle≤2%

5. Essentially independent of operating temperature

**7. Test circuits and waveforms**

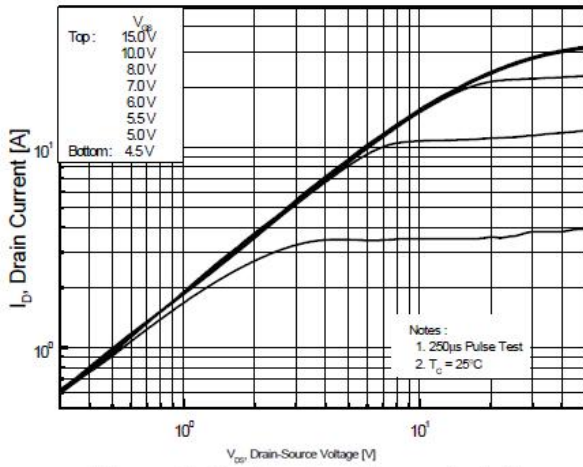


Figure 1. On-Region Characteristics

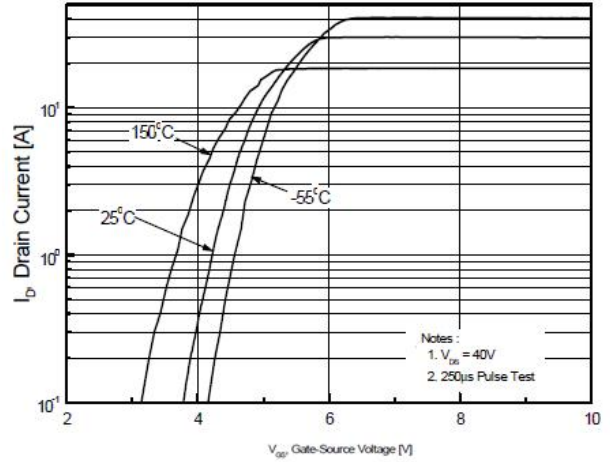


Figure 2. Transfer Characteristics

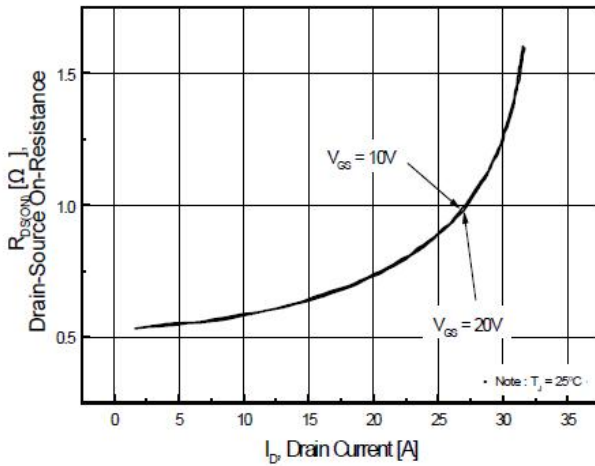


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

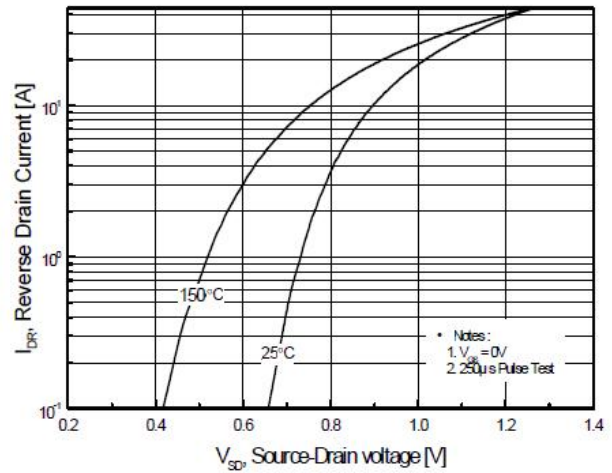


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

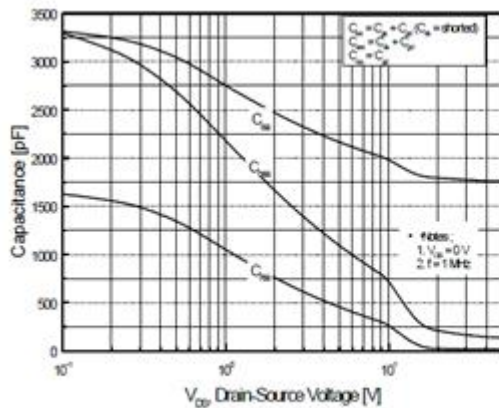


Figure 5. Capacitance Characteristics

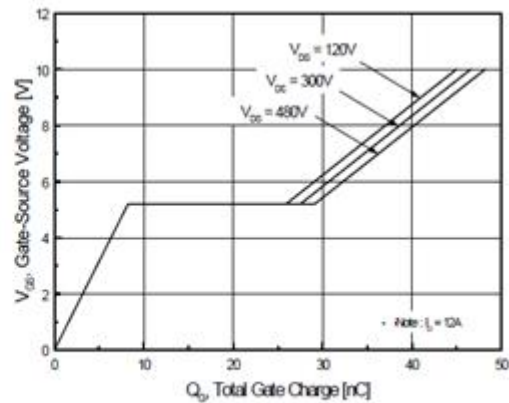


Figure 6. Gate Charge Characteristics

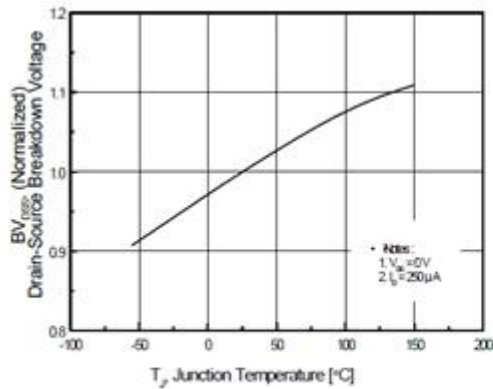


Figure 7. Breakdown Voltage Variation vs Temperature

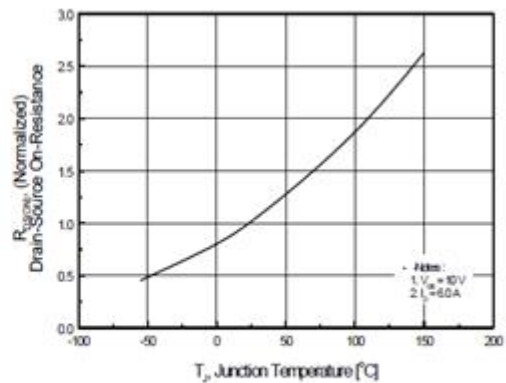


Figure 2. Transfer Characteristics

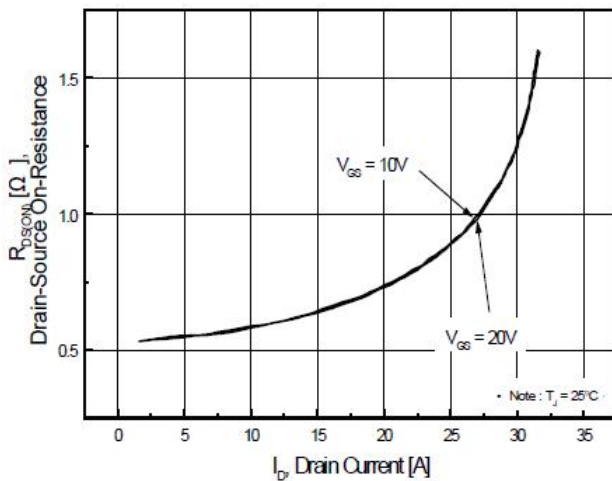


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

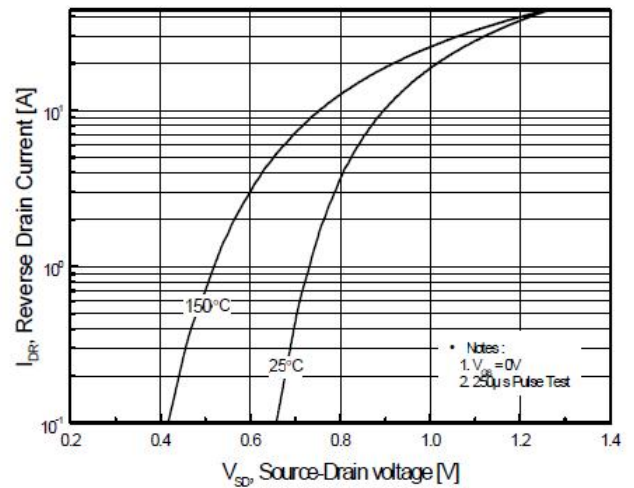


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

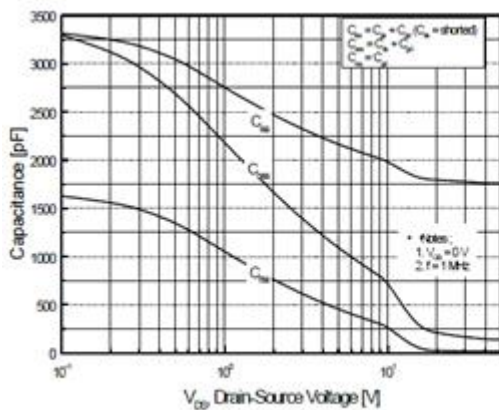


Figure 5. Capacitance Characteristics

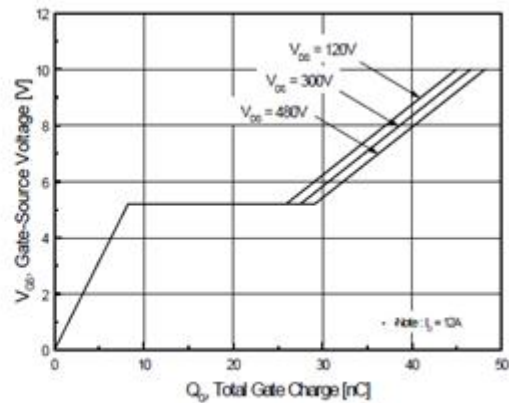


Figure 6. Gate Charge Characteristics

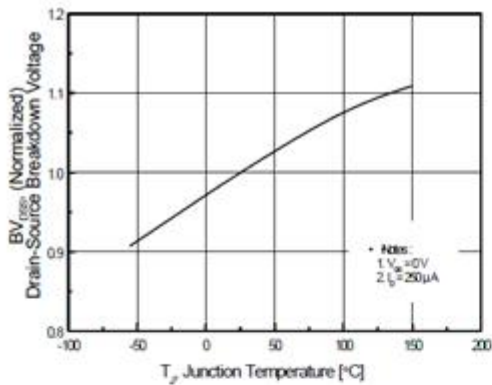


Figure 7. Breakdown Voltage Variation vs Temperature

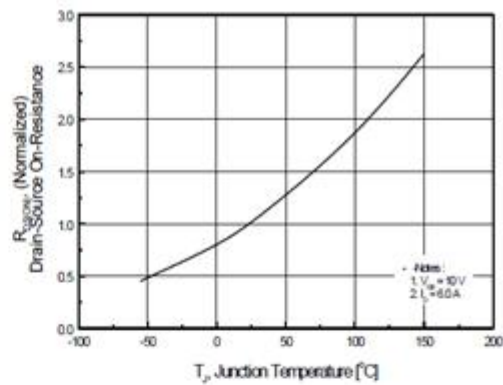


Figure 8. On-Resistance Variation vs Temperature

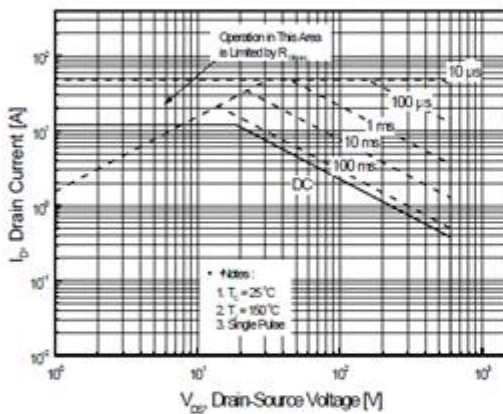


Figure 9-1. Maximum Safe Operating Area for TO220

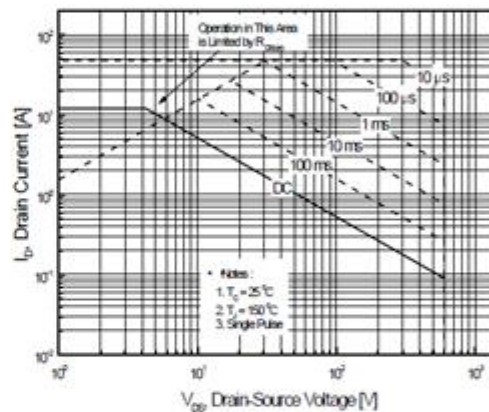


Figure 9-2. Maximum Safe Operating Area for TO220F

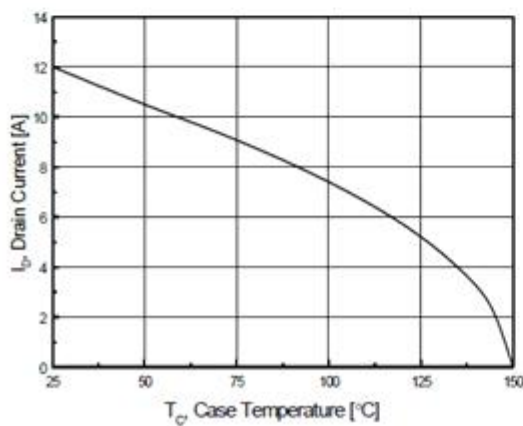


Figure 10. Maximum Drain Current vs Case Temperature

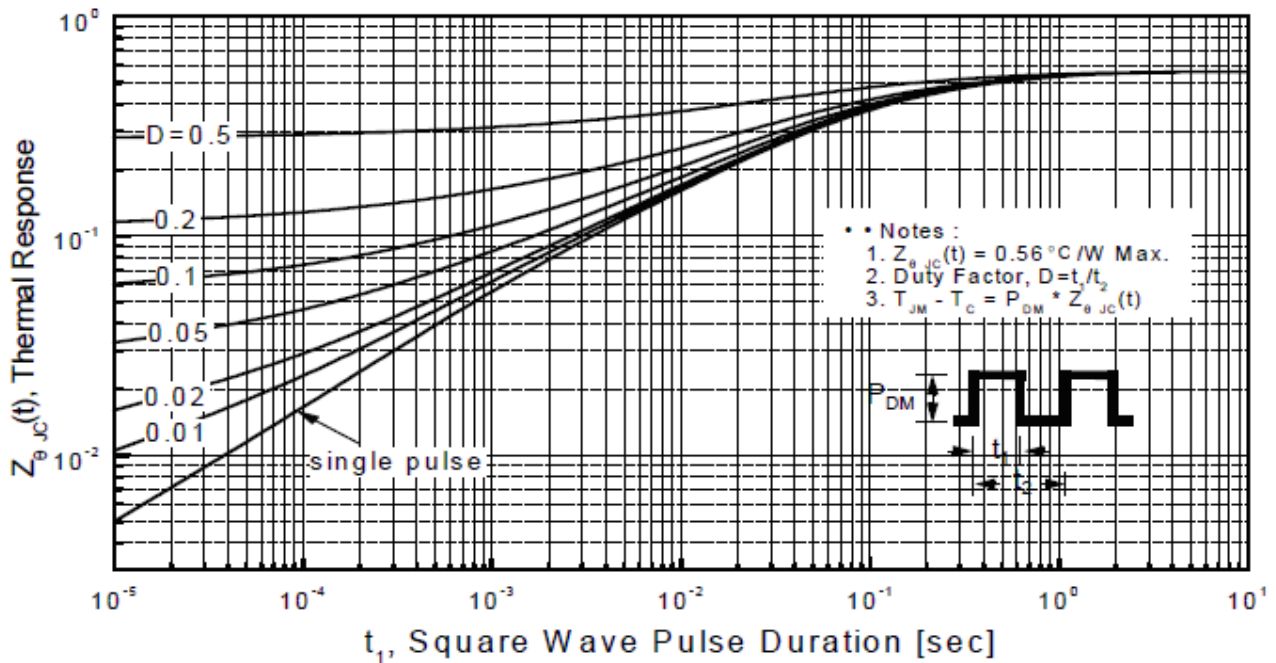


Figure 11-1. Transient Thermal Response Curve for TO220

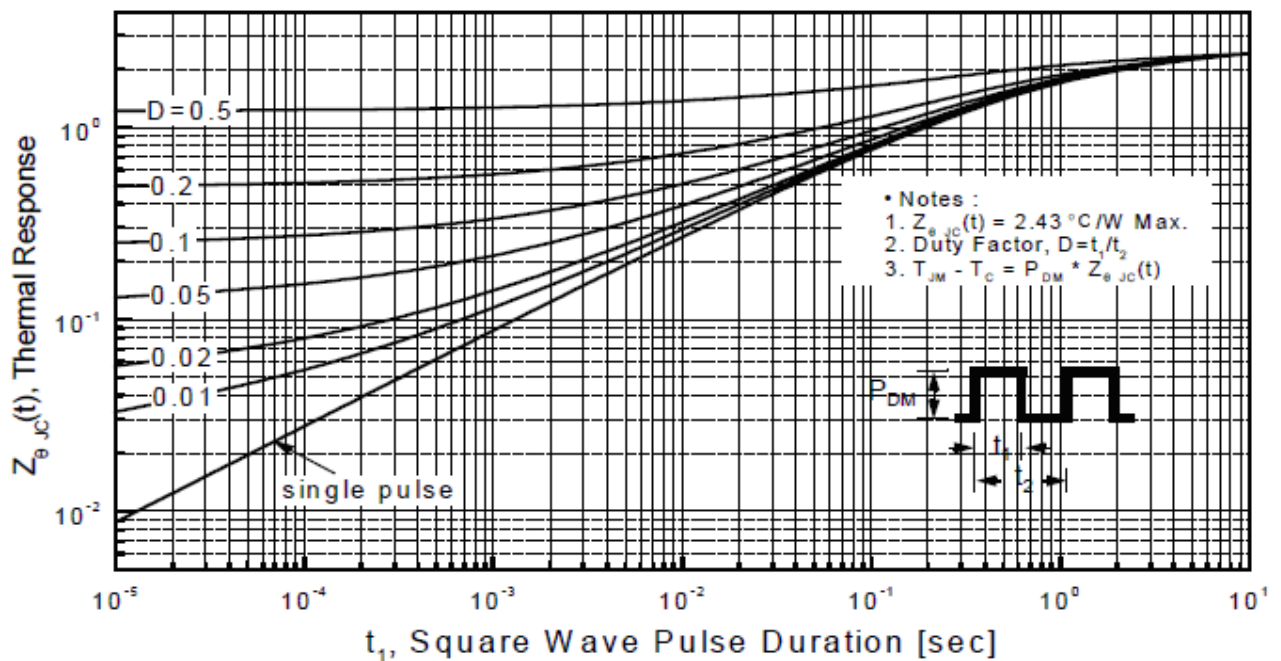


Figure 11-2. Transient Thermal Response Curve for TO220F